

Docket No.: 60188-570

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of
Katsuki NAGAHASHI, et al.

Serial No.: 10/632,960

Filed: August 04, 2003

: Customer Number: 20277
: Confirmation Number: 4471
: Group Art Unit: 2858
: Examiner: not yet assigned

For: ACCELERATED TEST METHOD FOR FERROELECTRIC MEMORY DEVICE

INFORMATION DISCLOSURE STATEMENT

Mail Stop IDS
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

10/632,960

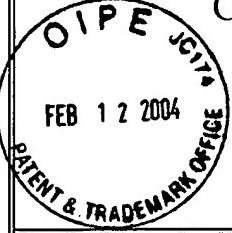
Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION  FEB 12 2004 (PTO-1449)				ATTY. DOCKET NO. 60188-570	SERIAL NO. 10/632,960		
				APPLICANT Katsuki NAGAHASHI, et al.			
				FILING DATE August 04, 2003	GROUP 2858		
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ₂ (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
	US	5,337,279	08/09/1994	Gregory et al.			
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FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number 4-Kind Codes (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
		WO 01/22426 A1	03/29/2001	CELIS SEMICONDUCTOR CORPORATION			
		EP 0 836 197 A2	04/15/1998	MATSUSHITA ELECTRONICS CORPORATION			
		DE 100 58 779 A1	06/13/2002	INFINEON TECHNOLOGIES AG		x	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
		TRAYNOR S.D., et al. "Capacitor test simulation of retention and imprint characteristics for ferroelectric memory operation." Integrated Ferroelectrics, New York, NY, vol. 16, 1997, pages 63-76, XP-002099256					
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.